REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Drawing updated to reflect current requirements. Editorial changes throughout. – drw	00-12-13	Raymond Monnin
B	Redraw. Update drawing to current requirements. - drw	11-06-08	Charles F. Saffle
C	Update paragraphs to MIL-PRF-38535 requirements. - drw	18-04-02	Charles F. Saffle
D	Make change to the ON Resistance test limit for device type 01 subgroup 2, 3 as specified under Table I by deleting 400 Ω and replacing with 425 Ω. - ro	19-06-06	Charles F. Saffle

THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

REV																			
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REV STATUS	REV	D	D	D	D	D	D	D	D	D	D	D	D	D					
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13					

PMIC N/A

PREPARED BY
Marcia B. Kelleher

CHECKED BY
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APPROVED BY
Michael A. Frye

DRAWING APPROVAL DATE
88-12-08

REVISION LEVEL
D

STANDARD MICROCIRCUIT DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

DLA LAND AND MARITIME
COLUMBUS, OHIO 43218-3990
https://www.dla.mil/LandandMaritime

MICROCIRCUIT, LINEAR, 8-CHANNEL, JFET ANALOG MULTIPLEXERS, MONOLITHIC SILICON

SIZE	CAGE CODE	
A	**67268**	**5962-87716**

SHEET 1 OF 13

DSCC FORM 2233
APR 97

5962-E334-19

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:

5962-87716	01	E	A
Drawing number	Device type (see 1.2.1)	Case outline (see 1.2.2)	Lead finish (see 1.2.3)

1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

Device type	Generic number	Circuit function
01	MUX-08A	8-channel JFET analog multiplexer
02	MUX-08B	8-channel JFET analog multiplexer

1.2.2 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	Terminals	Package style
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
2	CQCC1-N20	20	Square leadless chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

Positive supply voltage (V_{CC}) ..... +18 V dc
Negative supply voltage (V_{EE}) ..... -18 V dc
Logic input voltage ..... (-4 V or V_{EE}) to V_{CC}
Analog input voltage ..... V_{EE} - 20 V to V_{CC} + 20 V
Maximum current through any pin ..... 25 mA
Storage temperature range ..... -65°C to +150°C
Power dissipation (P_D) 1/ ..... 500 mW
Lead temperature (soldering, 60 seconds) ..... 300°C
Junction temperature (T_J) ..... 150°C
Thermal resistance, junction-to-case (θ_{JC}) ..... See MIL-STD-1835
Thermal resistance, junction-to-case (θ_{JA}):
  Case E ..... 91°C/W
  Case 2 ..... 110°C/W

1/ Derate above 100°C, 10 mW/°C.

1.4 Recommended operating conditions.

Positive supply voltage (V_{CC})	+15 V dc
Negative supply voltage (V_{EE})	-15 V dc
Ambient operating temperature range (T_A)	-55°C to +125°C
Digital “1” input voltage (V_{IH})	2.0 V min
Digital “0” input voltage (V_{IL})	0.8 V max
Analog voltage range (V_A)	±10 V max

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at https://quicksearch.dla.mil.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.2.5 Switching time waveforms. The switching time waveforms shall be as specified on figure 7.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.5.1 Certification/compliance mark. A compliance indicator “C” shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator “C” shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DLA Land and Maritime -VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DLA Land and Maritime -VA shall be required for any change that affects this drawing.

3.9 Verification and review. DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ V_{CC} = +15 V, V_{EE} = -15 V unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Positive supply current	I_{CC}		1	All		12	mA
			2, 3			15	
Negative supply current	I_{EE}		1	All	-3.8		mA
			2, 3		-5		
"ON" resistance	R_{ON}	-10 V $\le V_{SOURCE} \le$ +10 V, I_{SOURCE} = 200 µA	1	01		300	Ω
				02		400	
			2, 3	01		425	
				02		500	
"ON" resistance change with change in source voltage	$\Delta R_{ON}/\Delta V_{SOURCE}$	-10 V $\le V_{SOURCE} \le$ +10 V, I_{SOURCE} = 200 µA 1/	1	01		5	%
			2			7	
			3			6	
			1	02		7	
			2			8	
			3			8	
R_{ON} MATCH between switches	R_{ON} MATCH	V_{SOURCE} = 0 V, I_{SOURCE} = 200 µA 1/, 2/	1	01		15	%
			2			20	
			3			18	
			1	02		20	
			2			23	
			3			23	
Digital input current	I_{IN}	V_{IN} = 0.4 V to 15 V	1	All		±10	µA
			2, 3			±20	
Digital "0" enable current	$I_{IN(EN)}$	$V_{IN(EN)}$ = 0.4 V	1	All		±10	µA
			2, 3			±20	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - continued.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ V_{CC} = +15 V, V_{EE} = -15 V unless otherwise specified		Group A subgroups	Device type	Limits		Unit
						Min	Max	
Source current (Switch "OFF")	I_{SOURCE} (OFF)	V_{SOURCE} = 10 V V_{DRAIN} = -10 V 3/	V_{IL} = 0.8 V	1, 3	01		±1	nA
			V_{IL} = 0.7 V	2			±25	
			V_{IL} = 0.8V	1	02		±2	
			V_{IL} = 0.7 V	2			±50	
			V_{IL} = 0.8 V	3			±25	
Drain current (Switch "OFF")	I_{DRAIN} (OFF)	V_{SOURCE} = 10 V V_{DRAIN} = -10 V 3/	V_{IL} = 0.8V	1, 3	01		±1	nA
			V_{IL} = 0.7 V	2			±100	
			V_{IL} = 0.8 V	1	02		±2	
			V_{IL} = 0.7 V	2			±500	
			V_{IL} = 0.8 V	3			±100	
Leakage current (Switch "ON")	$I_{DRAIN(ON)}$+ $I_{SOURCE(ON)}$	V_{IH} = 2 V, V_{SOURCE} = V_{DRAIN} = +10 V 3/		1, 3	01		±1	nA
				2			±100	
				1	02		±2	
				2			±500	
				3			±100	
Analog voltage range	V_A	1/		1, 2, 3	All	±10		V
Digital "0" input voltage	V_{IL}	1/		1, 3	All		0.8	V
				2			0.7	
Digital "1" input voltage	V_{IH}	1/		1, 2, 3	All	2.0		V
Functional tests 4/		See 4.3.1c		1, 2, 3	All			
Switching time	t_{PHL}, t_{PLH}	V_{S1} = +10 V, V_{S8} = -10 V, R_L = 10 MΩ, C_L = 10 pF, see figures 4 and 7		9	All		2.1	µs
				10, 11 1/			3.5	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - continued.

Test	Symbol	Conditions $-55°C \le T_A \le +125°C$ V_{CC} = +15 V, VEE = -15 V unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Enable delay "ON"	$t_{ON(EN)}$	V_{S1} = -1.0 V, C_L = 10 pF, R_L = 1 kΩ, see figures 5 and 7	9	All		2.0	µs
			10, 11 1/			3.0	
Enable delay "OFF"	$t_{OFF(EN)}$	V_{S1} = -1.0 V, C_L = 10 pF, R_L = 1 kΩ, see figures 5 and 7	9	All		0.4	µs
			10, 11 1/			1.0	
Break-before-make delay	t_{OPEN}	$V_{S1} = V_{S8}$ = -1 V, T_A = 25°C, see figures 6 and 7	9	All	0.1		µs

1/ Guaranteed, if not tested, to the specified limits.

2/ R_{ON} match specified as a percentage of $R_{AVERAGE}$ where:

$$R_{AVERAGE} = \frac{1}{N} \sum_{i=1}^{N} R_i$$ with N = number of channels, R_i = each channel's "ON" resistance.

3/ Conditions applied to leakage tests insure worst case leakages.

4/ Verified by leakage tests.

Device type	01 and 02	
Case outline	E	2
Terminal number	Terminal symbol	
1	A_0	NC
2	ENABLE	A_0
3	V_{EE}	ENABLE
4	S1	V_{EE}
5	S2	S1
6	S3	NC
7	S4	S2
8	DRAIN	S3
9	S8	S4
10	S7	DRAIN
11	S6	NC
12	S5	S8
13	V_{CC}	S7
14	GND	S6
15	A_2	S5
16	A_1	NC
17		V_{CC}
18		GND
19		A_2
20		A_1

FIGURE 1. Terminal connections.

A_2	A_1	A_0	ENABLE	"ON" Channel
X	X	X	L	NONE
L	L	L	H	1
L	L	H	H	2
L	H	L	H	3
L	H	H	H	4
H	L	L	H	5
H	L	H	H	6
H	H	L	H	7
H	H	H	H	8

FIGURE 2. Truth table.

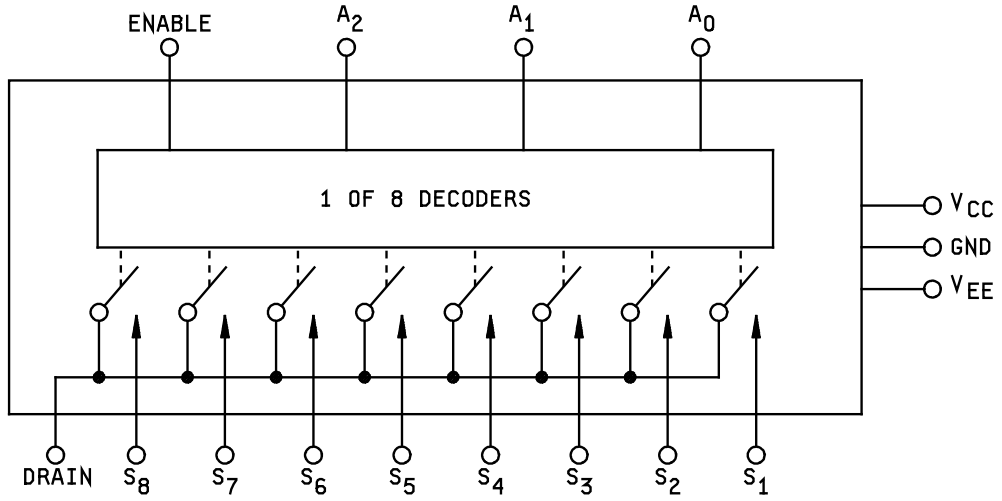

FIGURE 3. Logic diagram.

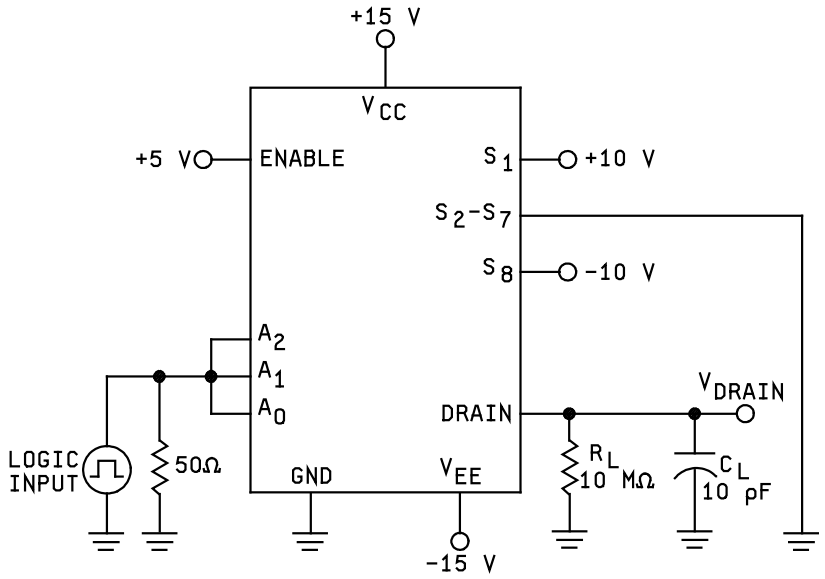

FIGURE 4. Transition time test circuit.

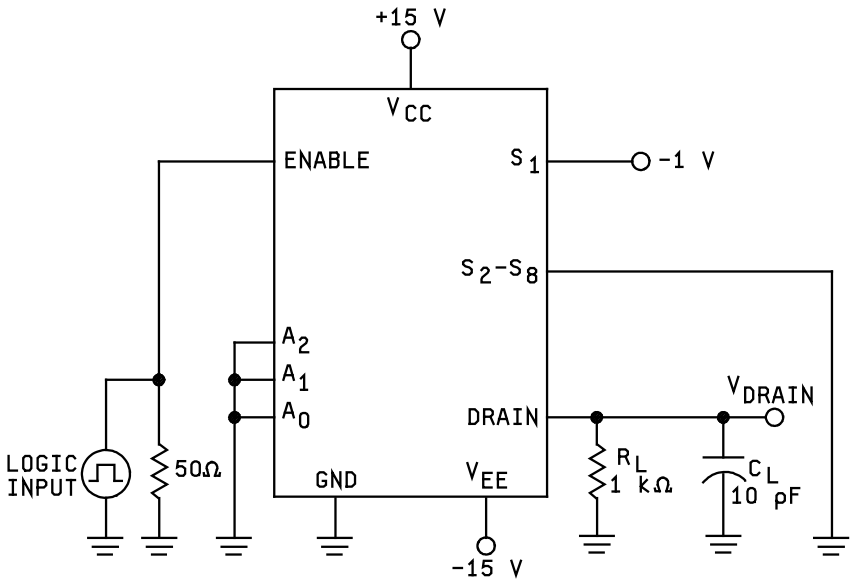

FIGURE 5. Enable delay time test circuit.

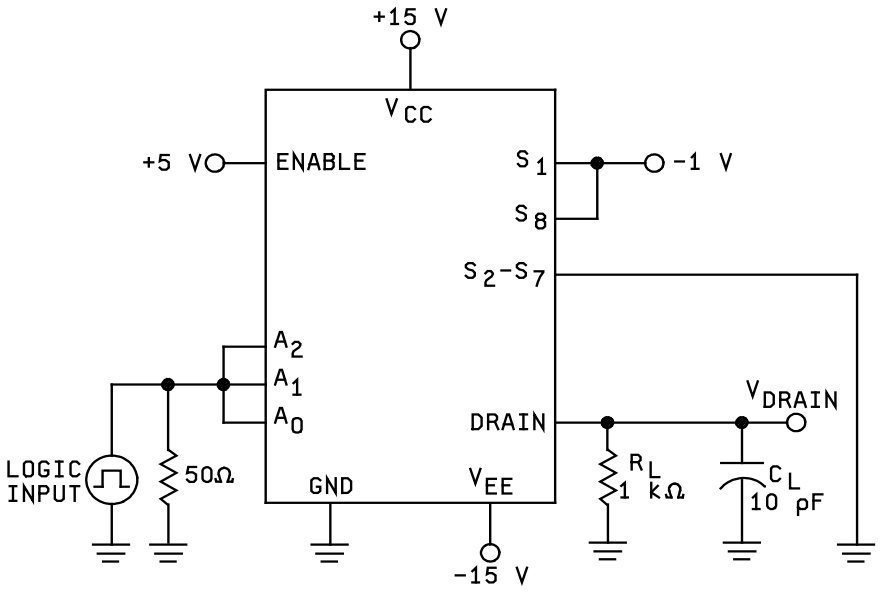

FIGURE 6. Break-before-make test circuit.

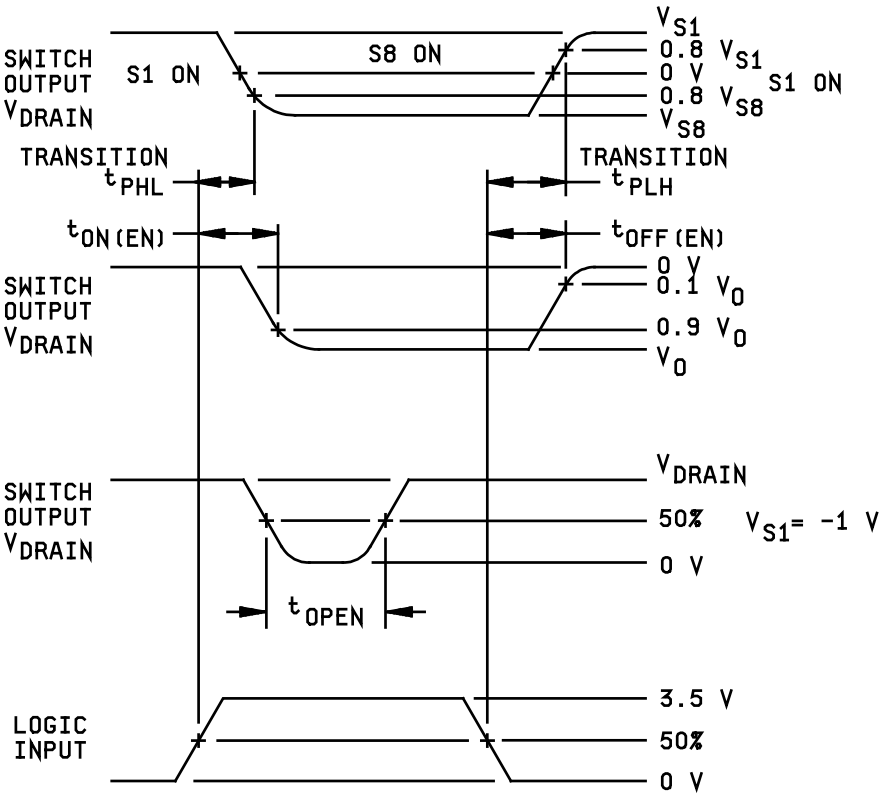

FIGURE 7. Switching time waveforms.

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, 7, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Leakage tests, performed on all channels, shall verify the truth table.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

(2) T_A = +125°C, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 9, (10, 11)**
Groups C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.
** Subgroups 10 and 11 are guaranteed, if not tested, to the limits specified in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.4 Record of users. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

6.5 Comments. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0540.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103 and QML-38535 (if QML). The vendors listed in MIL-HDBK-103 and QML-38535 (if QML) have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 19-06-06

Approved sources of supply for SMD 5962-87716 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at https://landandmaritimeapps.dla.mil/Programs/Smcr/.

Standard microcircuit drawing PIN 1/	Vendor CAGE number	Vendor similar PIN 2/
5962-8771601EA	24355	MUX-08AQ
5962-8771602EA	24355	MUX-08BQ
5962-87716022A	24355	MUX-08BRC

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
24355	Analog Devices Rt 1 Industrial Park PO Box 9106 Norwood, MA 02062 Point of contact: 804 Woburn Street Wilmington, MA 01887-3462